

# ***Mixed Modeling of a SAW Delay Line using VHDL***

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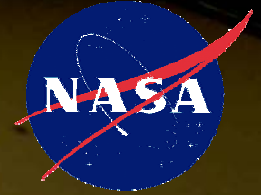
**NASA Langley Research Center**

**G. M. Atkinson**

**Virginia Commonwealth University**



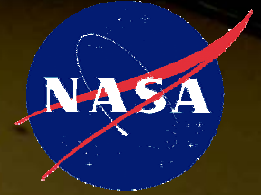
# Outline



- Motivation
- Introduction to Surface Acoustic Wave Devices
- Impulse Response Method
- VHDL Implementation
- Model integration into existing EDA Tools
- Results
- Conclusions

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# Motivation

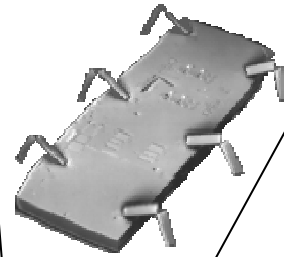
Exterior Inspection  
in space



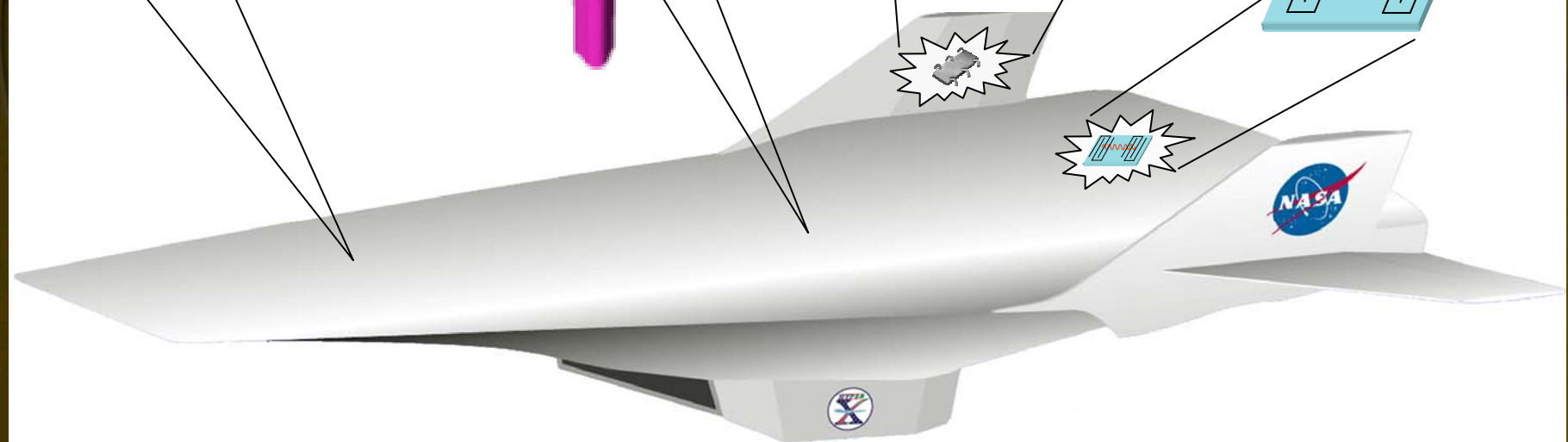
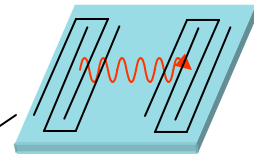
Exterior Inspection  
by hovering (Terrestrial)



Interior Inspection  
by walking (Terrestrial)



Interior SHM  
Wireless Sensors

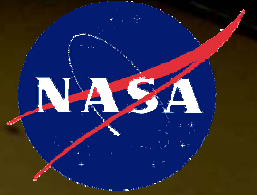


***Non-Destructive Evaluation (NDE)  
of Aerospace Vehicles***

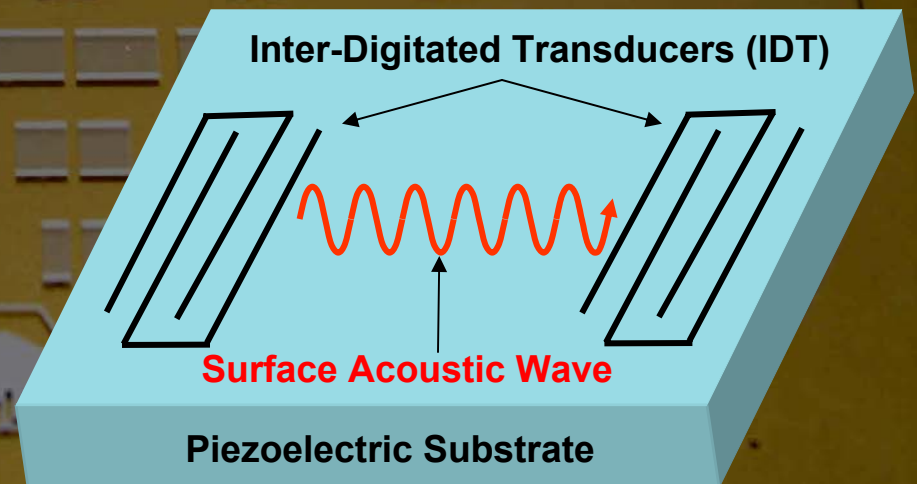




# Surface Acoustic Wave (SAW) Devices



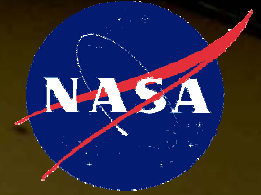
- Inexpensive
- Small (low mass and low volume)
- Extremely Low power (RF or Ambient)
- Versatile
  - Temperature sensors
  - Pressure sensors
  - Strain sensors
  - Ultrasonic sensors
  - Chemical sensors
  - Filters
  - Resonators
  - Signal Processing



Basic SAW Delay line Device.

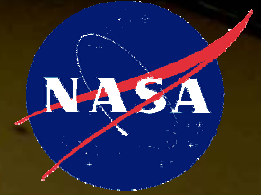


# *Impulse Response Method*

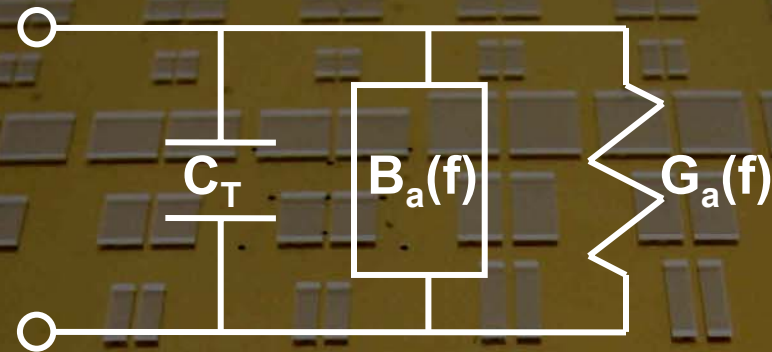


- The SAW device was modeled using the Impulse Response method<sup>1</sup>.
- This is a first order model only and does not take into account second order effects such as reflections, and Triple Transit Echoes (TTE).
- Simulates the mechanical, piezoelectric and electrical behavior.
- The model calculates the
  - Frequency response
  - Loss of the system
  - Admittance & Conductance
  - Electrical parameters such as the matching inductor.
- This model is valid only for transducers where at least one of the two IDTs is un-weighted.
- Assumes a constant metallization ratio of 0.5, and uniform finger overlap or aperture.

[1] Hartmann, C.S., Jr.; Bell, D.T.; Rosenfeld, R.C.; "Impulse Model Design of Acoustic Surface-Wave Filters", Microwave Theory and Techniques, IEEE Transactions on, Volume 21, Issue 4, Apr 1973, pp. 162 – 175

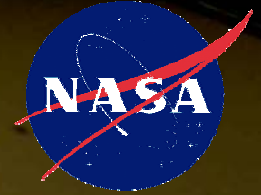


## *Circuit model used in the Impulse Response Method*

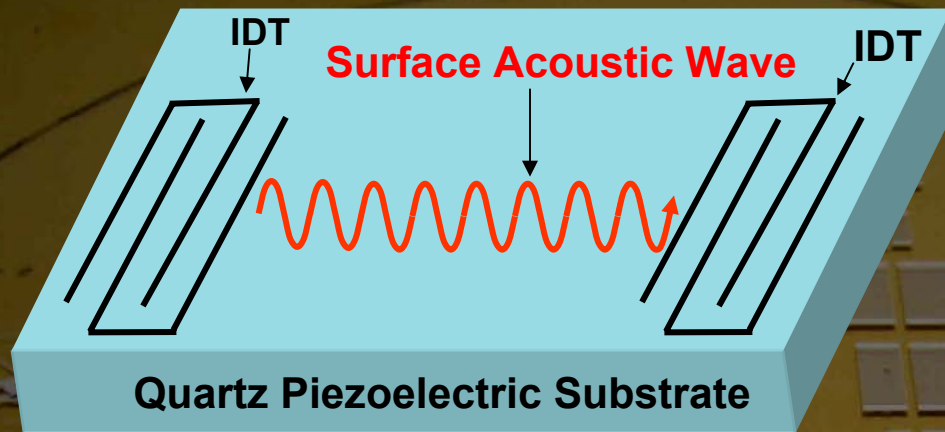


- **Uses the Mason equivalent circuit model.**
  - Based on Crossed field model.
  - $C_T$  is the total capacitance for an IDT.
  - $B_a(f)$  is the acoustic susceptance.
  - $G_a(f)$  is the radiation conductance.





## Example Parameters

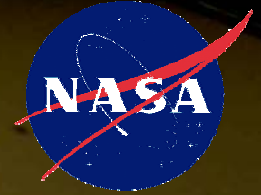


Basic SAW Delay line.

- SAW delay line that consists of two identical IDTs.
- The synchronous frequency is 52.563 MHz.
- The substrate is ST cut Quartz.
  - $C_s = 0.503385$  pf/cm (capacitance per finger pair, per cm)
  - $k = 0.04$  (piezoelectric coefficient)
  - $v = 3158$  m/s (acoustic velocity)
- NBW = 1.5 MHz (null bandwidth, or fractional bandwidth)
- The delay length between the two IDTs is 5 wavelengths.
- The source and load resistances are assumed to be  $50 \Omega$ .



# Parameter Optimization



Optimization of  
finger pairs

$$N_p = \text{round}\left(\frac{2}{\text{NBW}} f_0\right)$$

$$N_p = 70$$

$N_p \leq \text{round}(2.0/\text{NBW} \cdot f_0);$

Aperture width optimization

$$Z(f) = \frac{1}{(G_a + j(2\pi f C_T + B_a(f)))}$$

$$W_a = \frac{1}{R_{in}} \left( \frac{1}{2f_0 C_s N_p} \right) \frac{(4k^2 N_p)}{(4k^2 N_p)^2 + \pi^2}$$

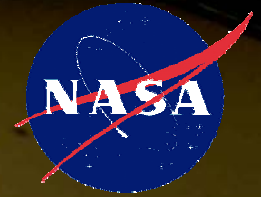
$$W_a = 2399.0 \mu m$$

```
function Wa_Optimized (f0,Np,Cs,k : real) return real is
variable Wa_opt1 : real := 1.0;
begin
    Wa_opt1 := (1.0/(2.0*Rin*Np*f0*Cs))*
    (4.0*Np*k*k)/(((4.0*Np*k*k)**2)+(math_pi**2));
return Wa_opt1;
end function Wa_Optimized;
```





# Conductance and Susceptance



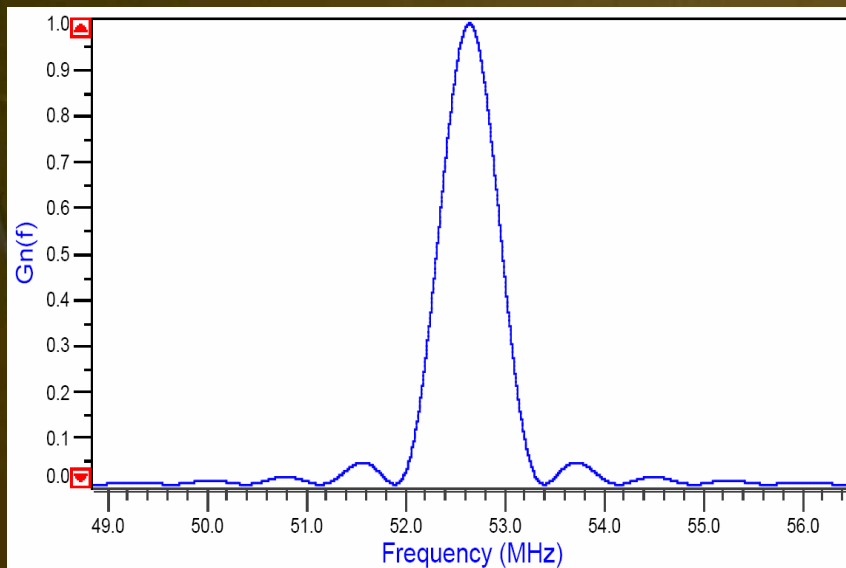
$$X = N_p \pi \frac{(f - f_0)}{f_0}$$

$$G_a(f) = 8k^2 C_s W_a f_0 N_p^2 \left| \frac{\sin(X)}{X} \right|^2$$

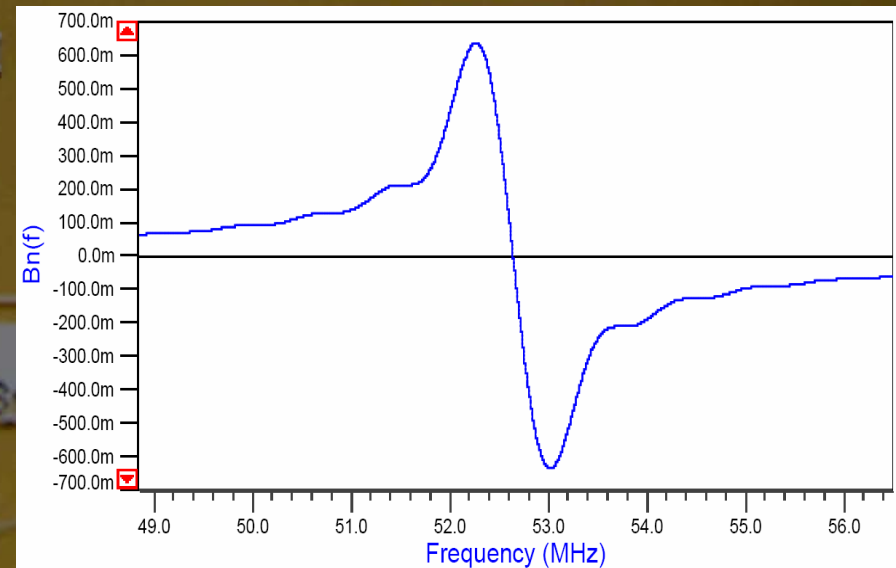
$$B_a(f) = \frac{G_a(f_0) \sin(2X) - 2X}{2X^2}$$

$$G_n(f) = \frac{G_a(f)}{G_a(f_0)}$$

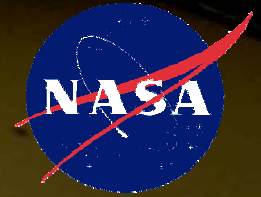
$$B_n(f) = \frac{B_a(f)}{G_a(f_0)}$$



**Radiation conductance  
of the SAW delay line.**

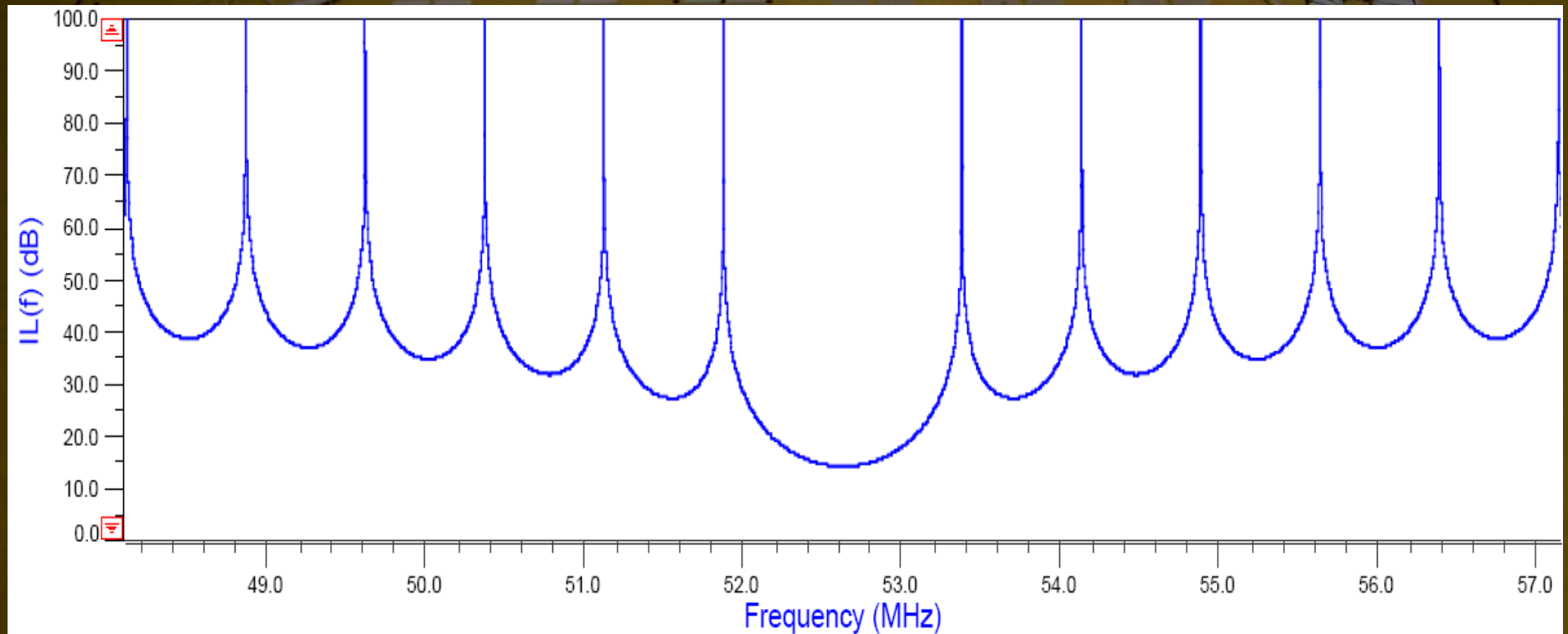


**Acoustic susceptance of  
the SAW delay line.**



# Insertion Loss

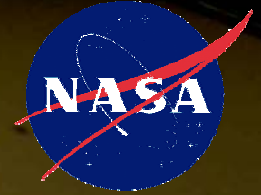
$$IL(f) = -10 \log \left[ \frac{2G_a(f)R_g}{\left(1 + G_a(f)R_g\right)^2 + \left[R_g(2\pi fC_T + B_a(f))\right]^2} \right]$$



Insertion Loss of the SAW delay line.



# Frequency Response

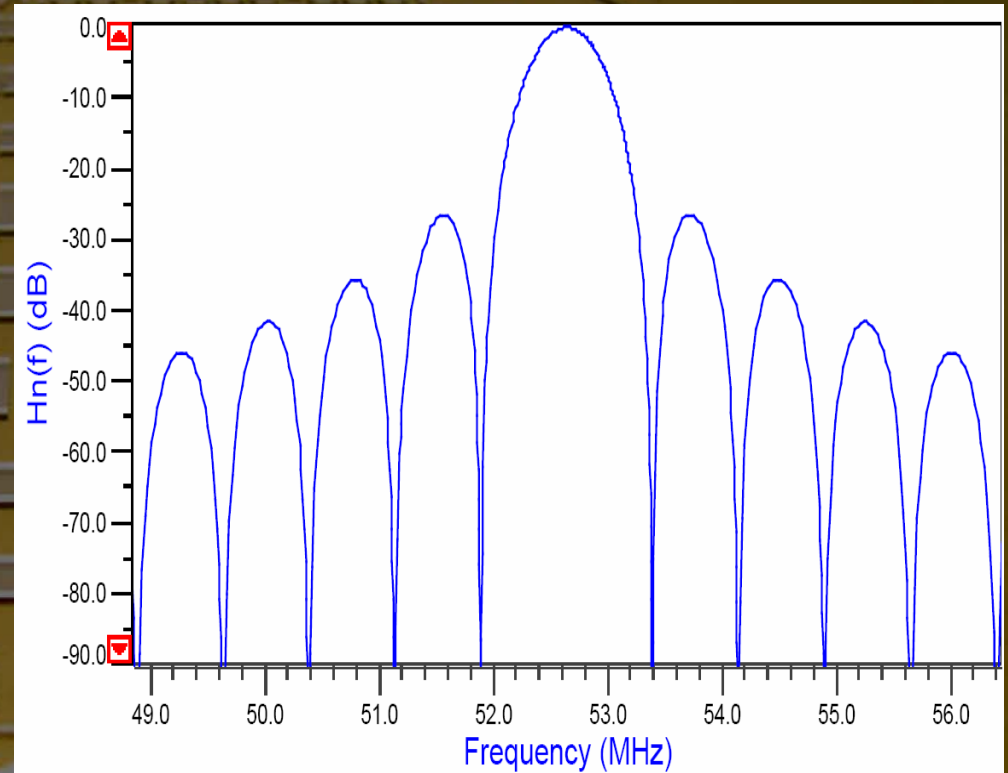


$$X = N_p \pi \frac{(f - f_0)}{f_0}$$

$$|H(f)| = 2k \sqrt{(C_s f_0) N_p} \frac{\sin(X)}{X}$$

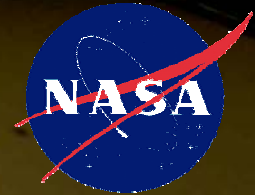
$$H_T(f) \cong H_1(f) \cdot H_2(f)$$

$$H_n(f) = 20 \log \left( \left| \frac{H_1(f) H_2(f)}{H_1(f_0) H_2(f_0)} \right| \right)$$



Frequency response of the SAW delay line about the center frequency.





# VHDL code for modeling an IDT

```
Library IEEE;
Use IEEE.Math_Real.all;
Use IEEE.Fundamental_Constants.all;
Entity Freq_Response is
  Port (Signal f0,Np,Cs,k : in real;
        Signal HT : out real);
End Freq_Response;

Architecture Freq_Domain of
  Freq_Response is
    Signal f,fmax,fmin : real := 1.0;

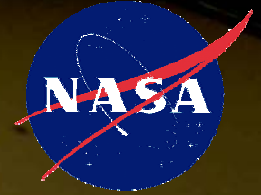
    Function x (f,f0,Np : real) return real is
      Variable result : real := 0.0;
      Begin
        If f = f0 then
          result := 1.0e-12;
        Else
          result := math_pi*Np*((f-f0)/f0);
        End If;
        Return result;
      End Function x;

      Function H (f,f0,Np,Cs,k : real) return real is
        Variable result : real;
        Begin
          result := 2.0*k*sqrt(Cs*f0)*Np*((sin(x(f,f0,Np))) / (x(f,f0,Np)));
          Return result;
        End Function H;

        Begin
          FR1: process is
            Begin
              Wait for 1fs;
              f <= f0*0.5;
              fmax <= f0*1.5;
              fmin <= f0*0.5;
              HT <= 20.0*log10(abs((H(f,f0,Np,Cs,k)**2.0) / H(f0,f0,Np,Cs,k)**2.0));
              Wait for f0*0.5*1.0e-6;
              While f <= fmax loop
                HT <= 20.0*log10(abs((H(f,f0,Np,Cs,k)**2.0) / H(f0,f0,Np,Cs,k)**2.0));
                Wait for f0*1.0e-10;
                f <= f+(f0*1.0e-4);
              End Loop;
            End Process FR1;
          End Architecture Freq_Domain;
```



## Example VHDL-AMS code for modeling an IDT

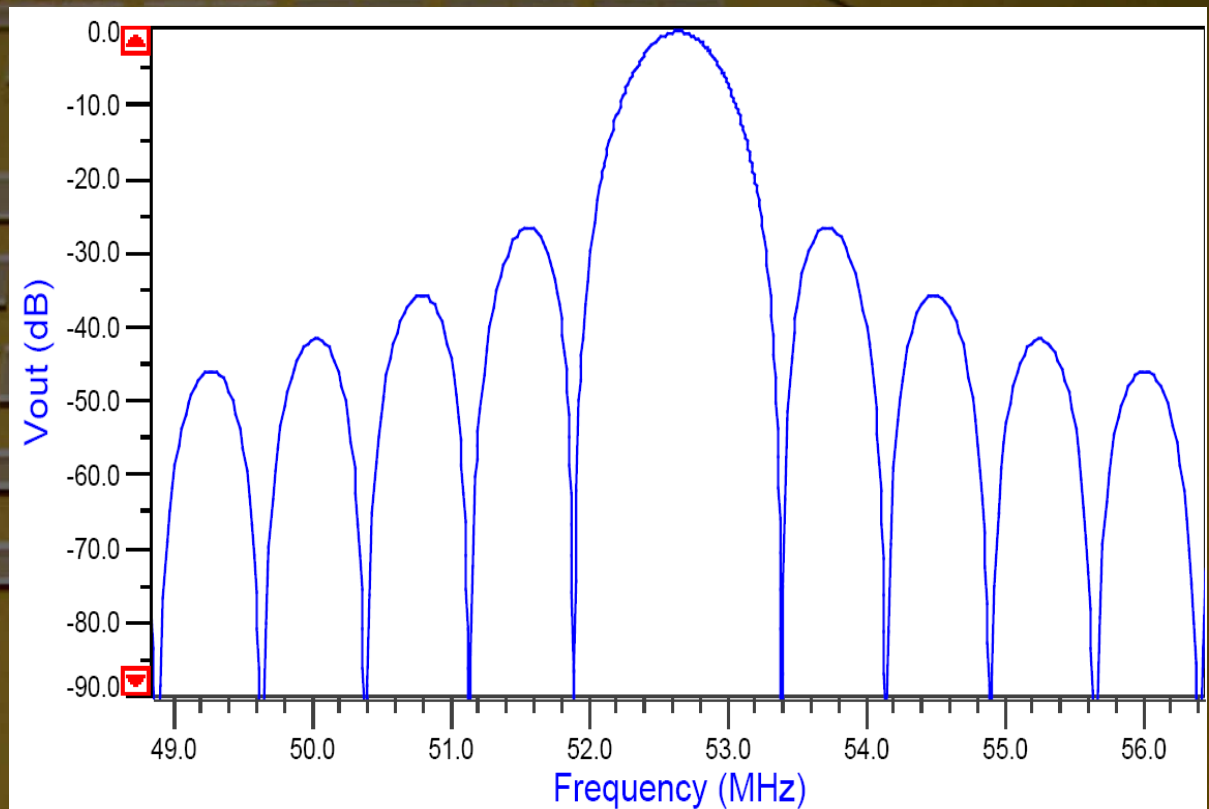


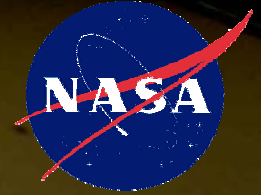
```
library IEEE;  
use IEEE.electrical_systems.all;  
library ieee;  
use ieee.math_real.all;  
use ieee.math_complex.all;  
use work.SAW_Pack1.all;
```

```
entity Freq_Response2 is  
  generic (f01,Np1,Cs4,k4:real);  
  port ( terminal input1 : electrical;  
         terminal output1 : electrical );  
end entity Freq_Response2;
```

```
architecture behavior of Freq_Response2 is  
  quantity vin across input1 to electrical_ref;  
  quantity vout across iout through output1 to electrical_ref;
```

```
begin  
  vout == 20.0*log10(abs((hh((vin),f01,Np1,Cs4,k4)**2.0)/hh(f01,f01,Np1,Cs4,k4)**2.0));  
end architecture behavior;
```



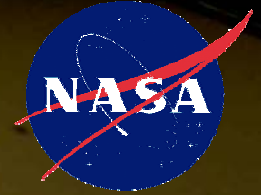


# Automated Report (VHDL Code Output)

## <<< SAW Delay Line Summary Report >>>

Finger Height	=	2.499000e-003 m
Aperture Height	=	2.399000e-003 m
Finger Width/Spacing	=	1.500009e-005 m
Number of Finger Pairs	=	7.000000e+001
Bus Bar Height	=	2.000000e-004 m
Delay Length (in wavelengths)	=	5.000000e+000
X Offset	=	0.000000e+000 m
Y Offset	=	0.000000e+000 m
Wavelength	=	6.000038e-005 m
Synchronous Frequency	=	5.263300e+007 Hz
Acoustic Velocity	=	3.158000e+003 m/s <sup>2</sup>
Series Matching Inductor	=	1.081672e-006 H
Minimum Insertion Loss (@f0)	=	1.424679e+001 dB
Total Capacitance (single IDT)	=	8.453344e-012 F



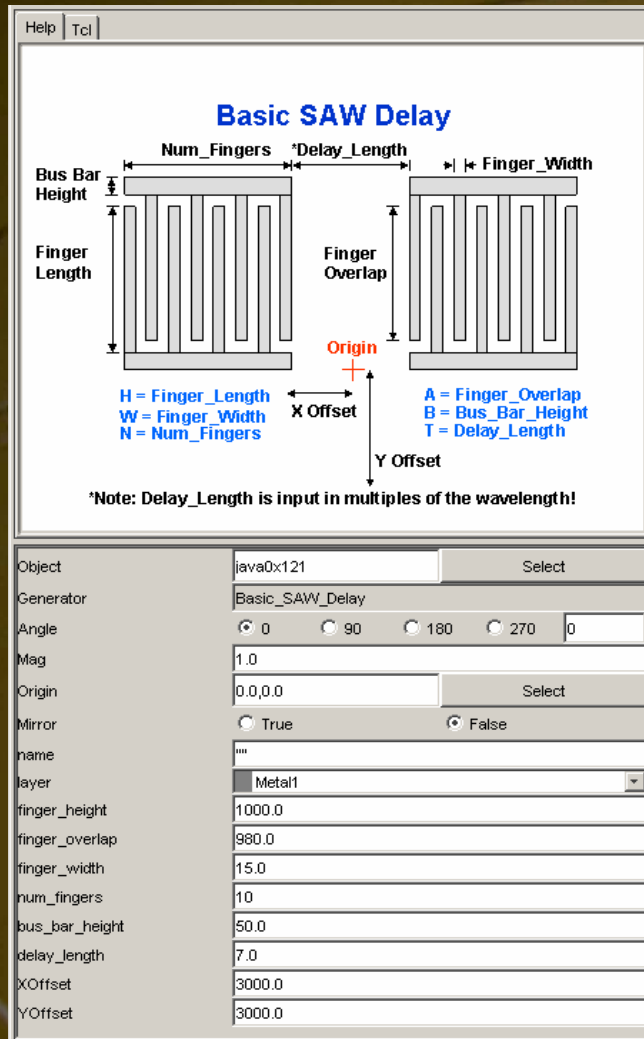
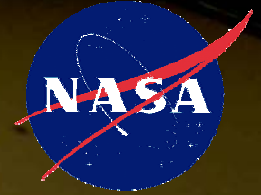


## *Integration of the models into existing EDA Tools*

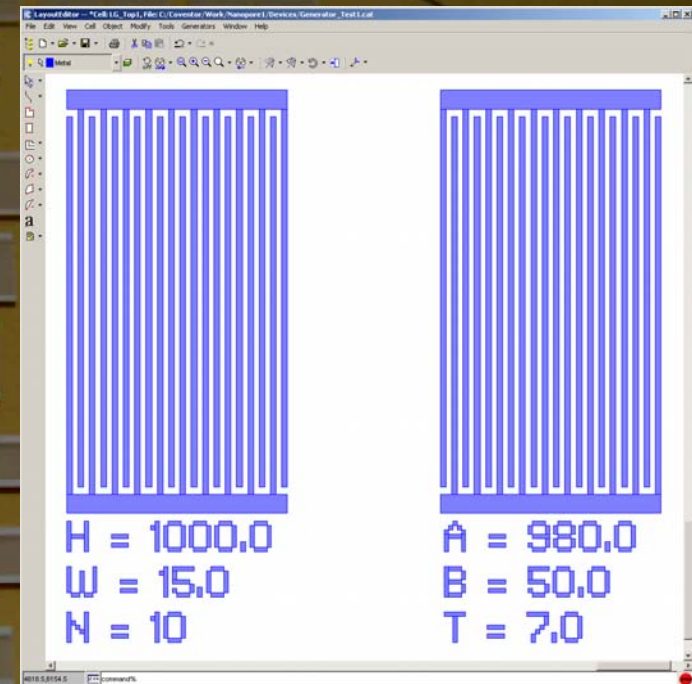
- Interface to *existing* layout tools.
  - Integrate VHDL models with layout software.
  - Parameterizable libraries of SAW devices using scripting language Tcl.
  - We integrated the tools into commercial Electronic Design Automation (EDA) Layout software for MEMS devices.
- The tools allow us to rapidly create, model, analyze and automatically generate device layouts (fabrication netlist).
- Enables a higher level of abstraction in the design process thus reducing the development time while increasing productivity.
- Allows access to existing tools
  - 3D Modeling
  - Finite Element Analysis (FEA)



# Parameterizable Library



**Layout Generator dialogue box.**  
This dialogue box is where the parameters for the basic SAW delay line are input.

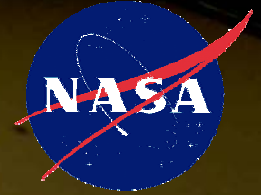


**Layout of a basic SAW delay line.**

- Finger heights of 1000  $\mu\text{m}$ .
- Finger widths of 15  $\mu\text{m}$ .
- 10 finger pairs
- aperture of 980  $\mu\text{m}$ .
- Bus bar heights are 50  $\mu\text{m}$ .
- Delay between the two IDTs is 7  $\lambda$ .



# Example Tcl code for a simple IDT structure



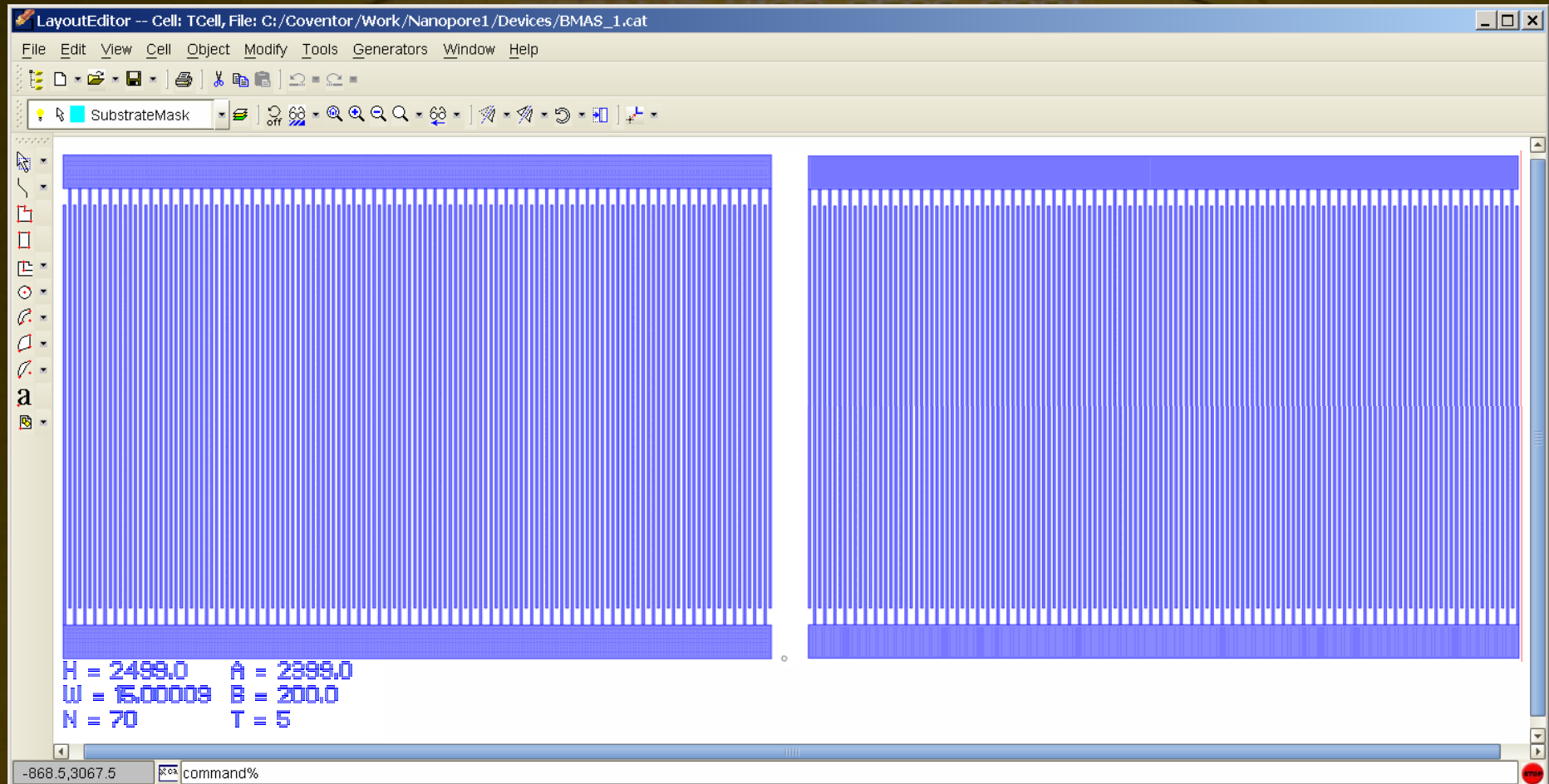
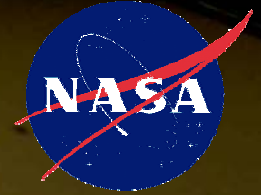
```
proc Basic_IDT { obj sname llayer dfinger_L dfinger_O dfinger_W inum_fingers dbus_bar_h }
{
  global error_count
  set Length [expr ($inum_fingers*4*$dfinger_W-$dfinger_W)]
  set Gap [expr ($dfinger_L-$dfinger_O)]

  # Top comb fingers
  #=====
  # Finger origin of the first finger
  set FOx [expr 0]
  # Loops over all movable fingers
  for {set i 1} {$i <= $inum_fingers} {incr i} {
    # Draws the movable comb finger
    set finger [cat:rectangle -layer $llayer $FOx [expr ($Gap+$dbus_bar_h)] [expr ($FOx+$dfinger_W)] [expr ($Gap+$dbus_bar_h+$dfinger_L)]]
    $obj addObject $finger
    # Next finger origin
    set FOx [expr $FOx + 4*$dfinger_W]
  }
  # Bottom comb fingers
  #=====
  # Finger origin of the first finger
  set FOx [expr (2*$dfinger_W)]
  # Loops over all fixed fingers
  for {set i 1} {$i <= [expr $inum_fingers]} {incr i} {
    # Draws the fixed comb finger
    set rect [cat:rectangle -layer $llayer $FOx $dbus_bar_h [expr $FOx+$dfinger_W] [expr ($dbus_bar_h+$dfinger_L)]]
    $obj addObject $rect
    # Next finger origin
    set FOx [expr $FOx + 4*$dfinger_W]
  }
  # Top Electrode
  #=====
  set rect [cat:rectangle -layer $llayer 0 [expr ($dbus_bar_h+$Gap+$dfinger_L)] $Length [expr ((2*$dbus_bar_h)+$Gap+$dfinger_L)]]
  $obj addObject $rect
  # Bottom electrode
  #=====
  set rect [cat:rectangle -layer $llayer 0 0 $Length $dbus_bar_h]
  $obj addObject $rect
  return
}
```





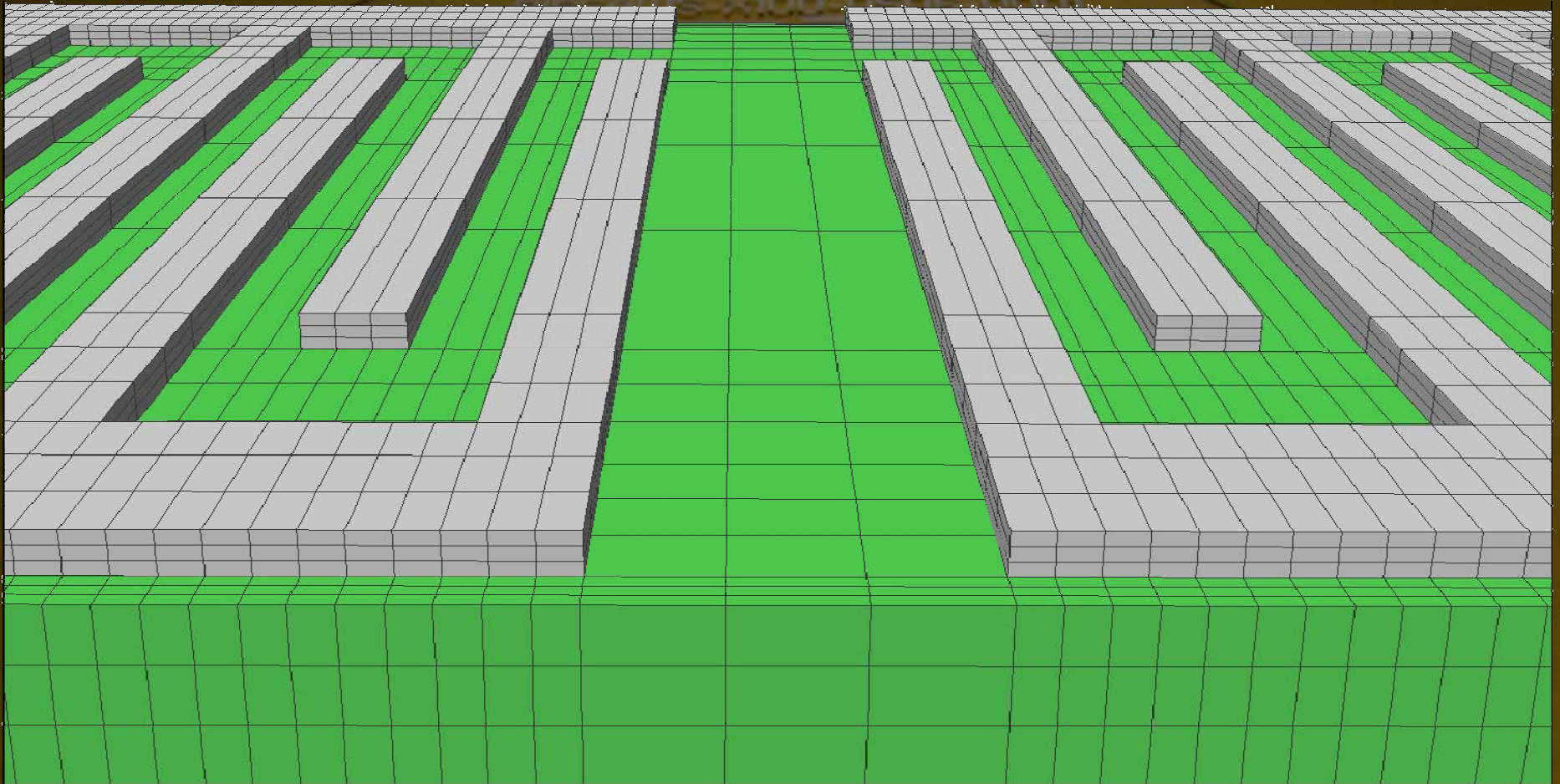
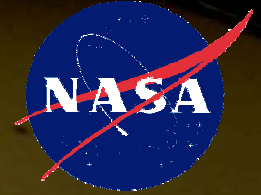
# *IDT Layout from Tcl*



**Automatically generated layout of the  
SAW delay line from the example.**



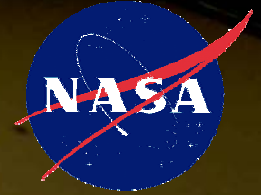
## 3-D Modeling



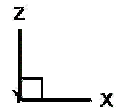
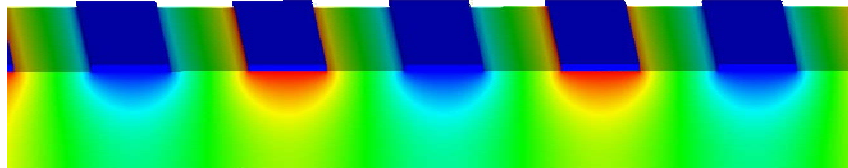
**Exaggerated 3-D Model of a SAW delay line.  
The model has been meshed using Manhattan bricks.**



# FEA Analysis



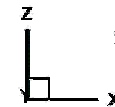
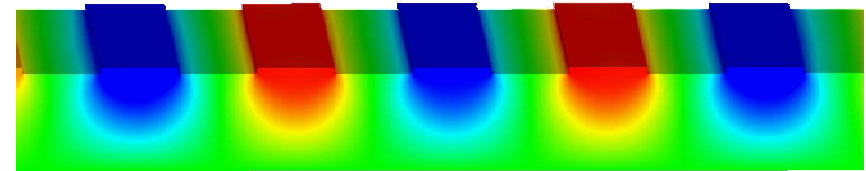
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Re[Potential]:



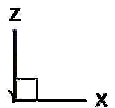
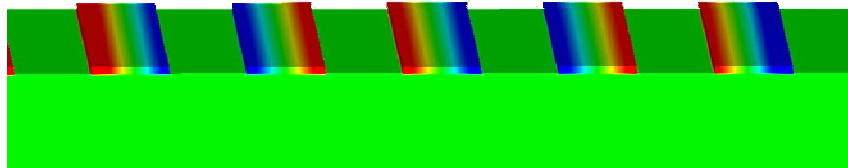
Potential



Displacement X:



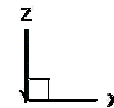
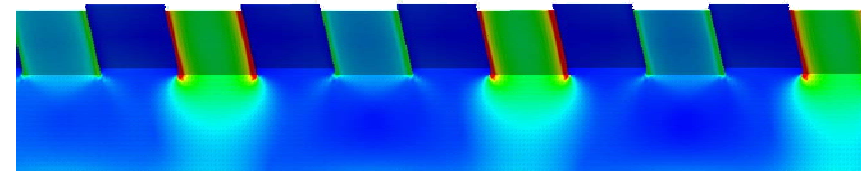
Displacement in X



Strain YY:



Strain<sub>YY</sub>



Principal Stress 1:



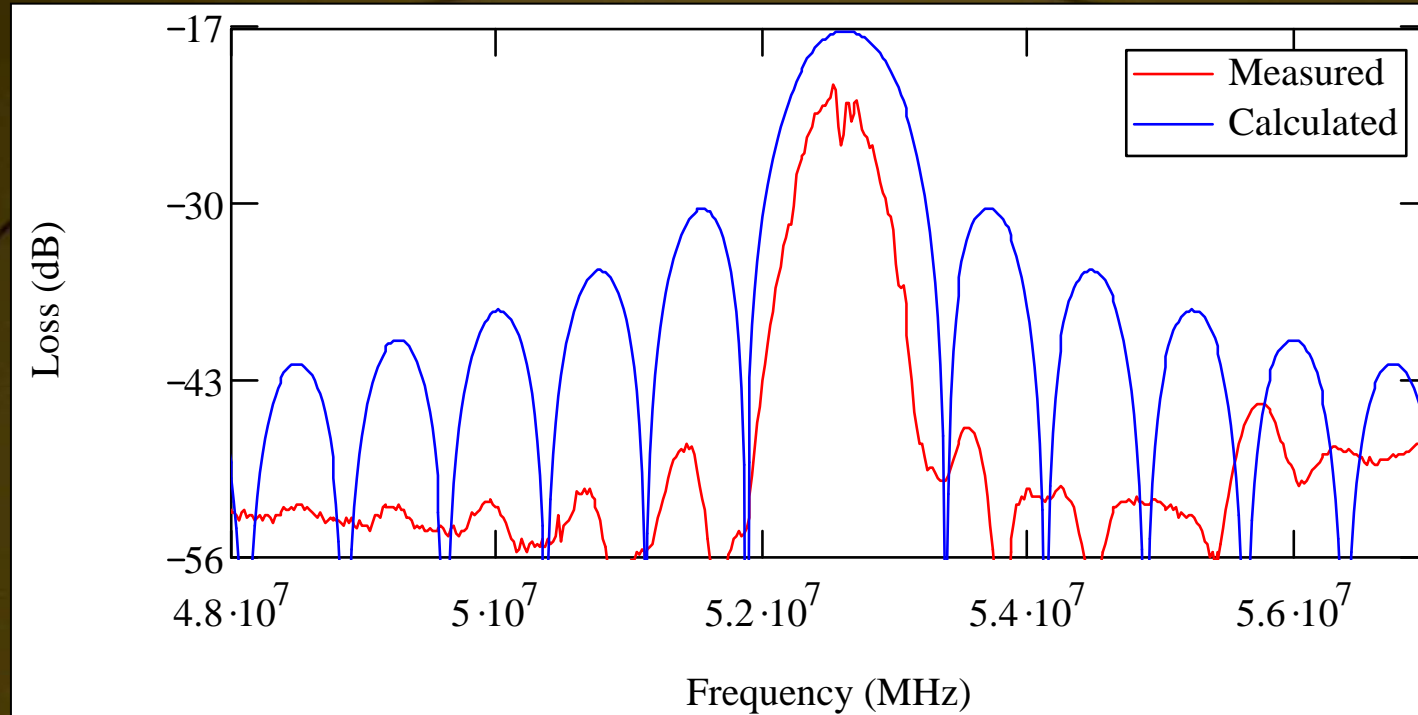
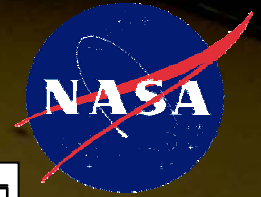
Principal Stress 1

Finite Element Analysis available from existing tools.

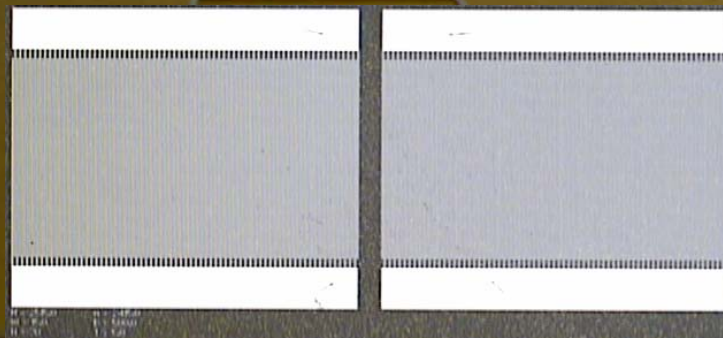




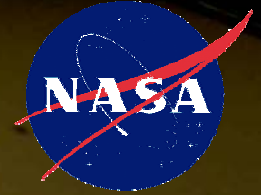
## Device Results



Frequency response of the SAW delay line device.



Picture of the device.

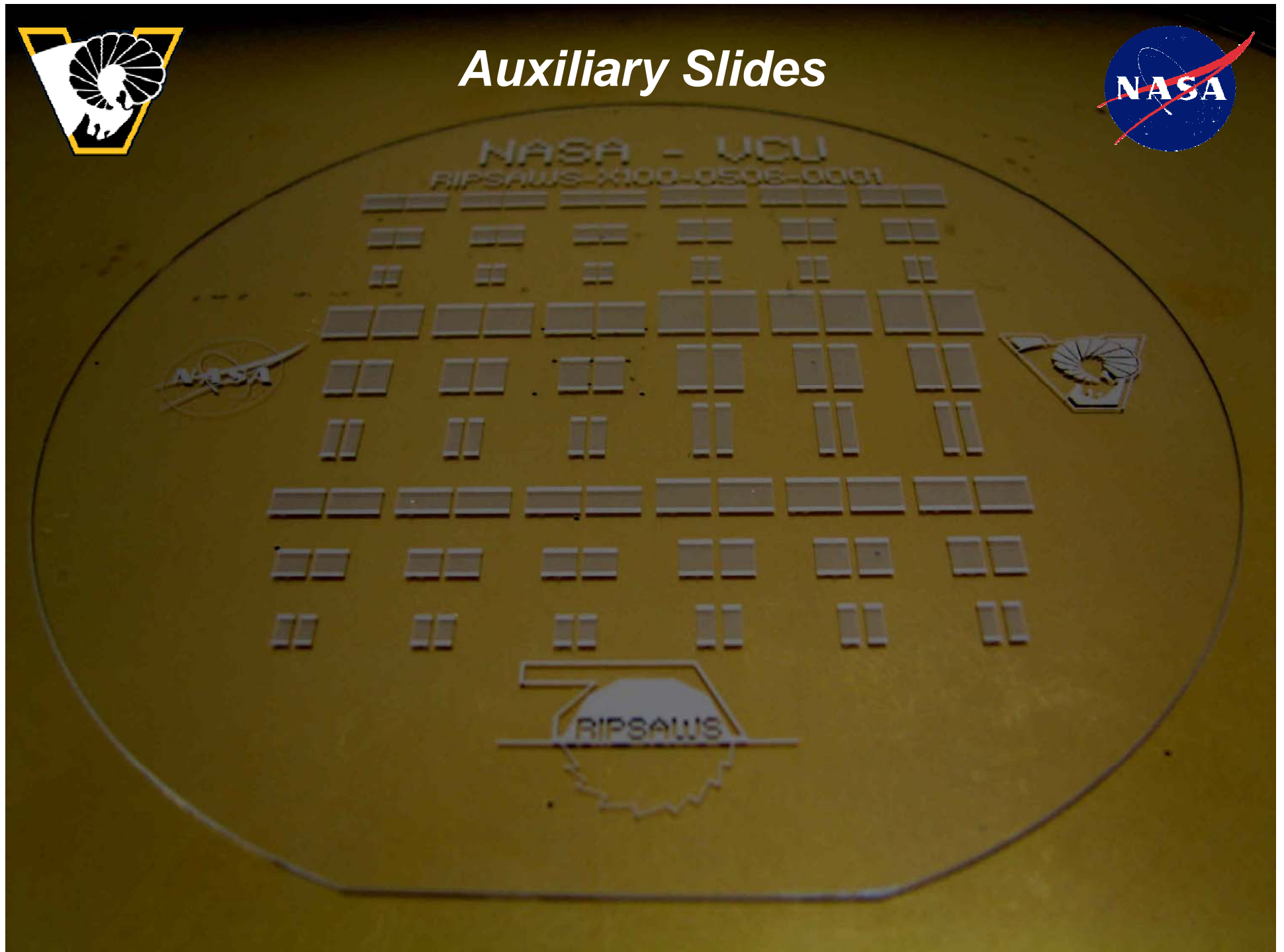
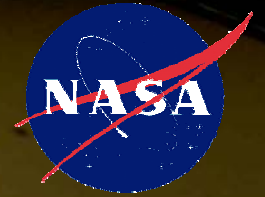


# Conclusion

- Developed models for a SAW delay line.
  - First order models only which use the Impulse Response Method.
  - Frequency response models in VHDL time domain analysis.
- Integrated the Models into existing EDA tools.
  - Parameterizable Library components using Tcl scripting language.
  - Automatic Layout Generation w/Annotation.
- Future work will include second order effects such as reflections, triple transit echoes, and temperature effects.
- We will continue to look for ways to model SAW devices in the frequency domain using the VHDL-AMS language.



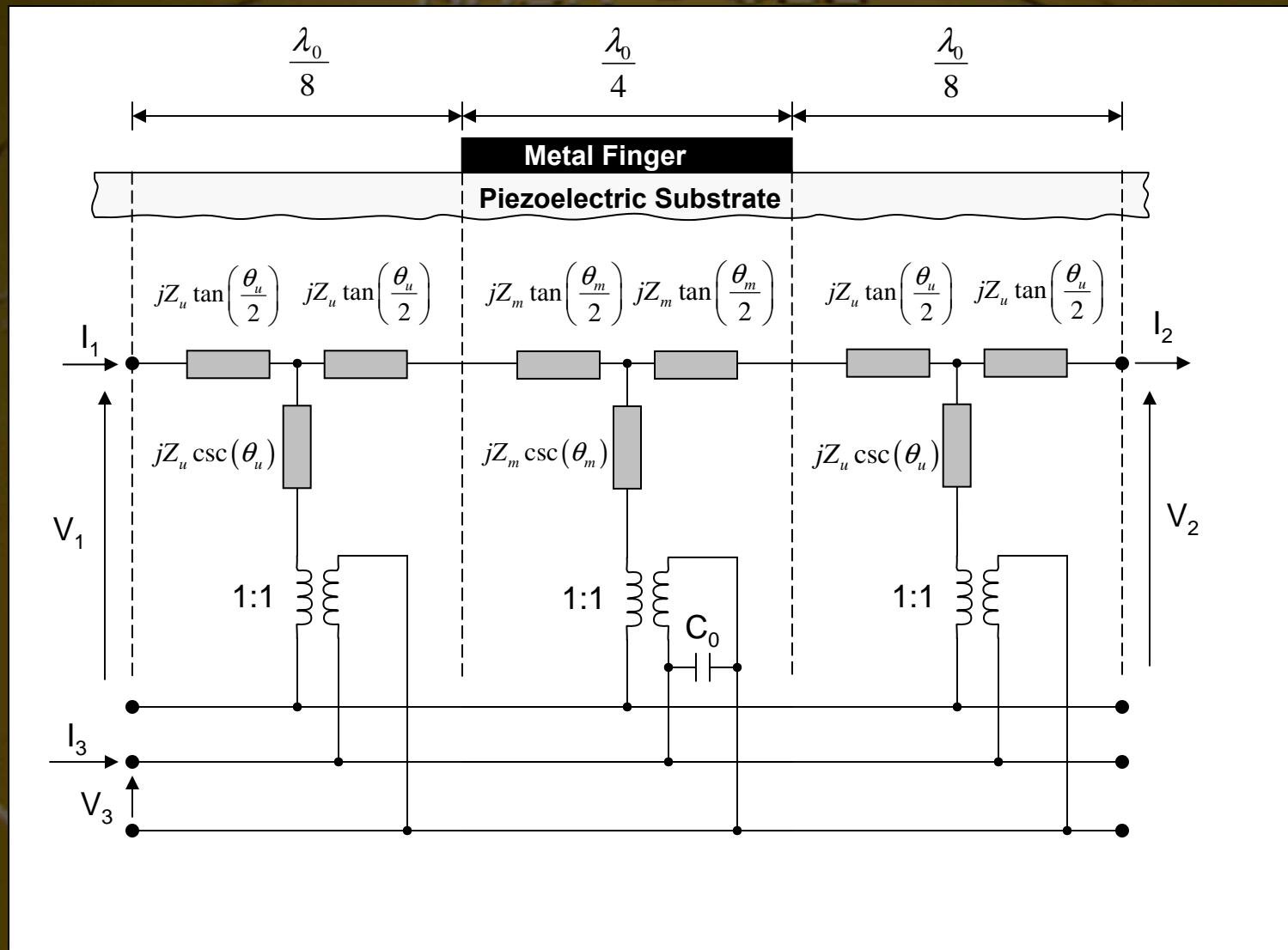
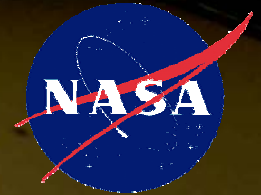
# Auxiliary Slides







## 2<sup>nd</sup> Order Model





# Passive Wireless SAW Sensor System

